

Appl. No. 10/707,560
Amdt. dated September 16, 2005
Reply to Office action of June 22, 2005

Amendments to the Claims:

Listing of Claims:

5 Claim 1 (currently amended) A method of repairing electrode pattern
 defects comprising:
 performing an inspection process for determine electrode
 pattern defects; and
 performing a first one-step repairing process with a conductive
 paste for repairing the electrode pattern ~~electrode~~ defects.

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 Claim 2 (original) The method of claim 1, wherein the electrode pattern is
 a sustain electrode pattern of a plasma display panel (PDP).

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 Claim 3 (original) The method of claim 2, wherein the sustain electrode is
 composed of a transparent conductive material or a metal
 conductive material.

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 Claim 4 (original) The method of claim 1, wherein the electrode pattern
 defects comprise a pit part such as a hole, an incomplete
 connection, or a broken connection.

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 Claim 5 (currently amended) The method of claim 4, wherein the first
 one-step repairing process is performed via either partially or
 completely filling the pit part with ~~[[a]]~~ the conductive paste.

 Claim 6 (original) The method of claim 5, wherein the conductive paste is
 selected from a group consisting of silver paste, ITO paste, IZO

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paste, gold paste, and silver glue.

Claim 7 (original) The method of claim 1, wherein the electrode pattern defects comprise salient parts.

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Claim 8 (original) The method of claim 7, wherein the method further comprises performing a second repairing process, the second repairing process removing the salient part by means of a laser beam.

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Claim 9 (original) The method of claim 1, wherein the inspection process comprises an optical inspection process or an electrical inspection process.

15 Claim 10 (currently amended) A method of repairing electrode pattern defects of a plasma display panel (PDP) comprising:

performing an inspection process to determine a ~~first~~ pit defect and a ~~second~~ salient defect of the plasma display panel;

20 performing a first one-step repairing process for filling the ~~first~~ pit defect; and

performing a second repairing process for removing the ~~second~~ salient defect.

25 Claim 11 (original) The method of claim 10, wherein the electrode pattern is composed of a transparent conductive material or a metal conductive material.

Claim 12 (currently amended) The method of claim 10, wherein the ~~first~~

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~~defect is a pit part of the electrode pattern such as~~ pit defect
comprises a hole, an incomplete connection, or a broken
connection.

5 Claim 13 (currently amended) The method of claim ~~[[12]]~~ 10, wherein the
first one-step repairing process fills the pit [part of the
electrode pattern] defect with a conductive paste.

10 Claim 14 (original) The method of claim 13, wherein the conductive paste
is selected from a group consisting of silver paste, ITO paste,
IZO paste, gold paste, and silver glue.

15 Claim 15 (currently amended) The method of claim 13, wherein the pit
[[part]] defect is completely filled up in the first one-step
repairing process.

20 Claim 16 (currently amended) The method of claim 13, wherein the pit
[[part]] defect is partially filled up in the first one-step
repairing process.

Claim 17 (cancelled)

25 Claim 18 (currently amended) The method of claim ~~[[17]]~~ 10, wherein the
second repairing process removes the salient [[part]] defect by
means of a laser beam.

Claim 19 (original) The method of claim 10, wherein the inspection process

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comprises an optical inspection process or an electrical inspection process, and the electrode pattern comprises a sustain electrode pattern, a bus electrode pattern, or an address electrode pattern.

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